TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7PA19AFE

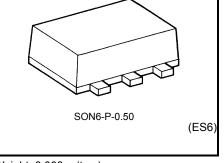
Chip Select Decoder

#### Features

- Operating voltage range: V<sub>CC</sub> = 1.4~3.6 V
- High-speed operation: t<sub>pd</sub> = 3.3 ns (max) at V<sub>CC</sub> = 3.0~3.6 V
  - t<sub>pd</sub> = 3.9 ns (max) at V<sub>CC</sub> = 2.3~2.7 V
    - t<sub>pd</sub> = 8.0 ns (max) at V<sub>CC</sub> = 1.65~1.95 V
    - t<sub>pd</sub> = 10.0 ns (max) at V<sub>CC</sub> = 1.4~1.6 V
- High-level output current:

 $I_{OH}/I_{OL} = \pm 24 \text{ mA (min) at } V_{CC} = 3.0 \text{ V}$  $I_{OH}/I_{OL} = \pm 18 \text{ mA (min) at } V_{CC} = 2.3 \text{ V}$  $I_{OH}/I_{OL} = \pm 4 \text{ mA (min) at } V_{CC} = 1.4 \text{ V}$ 

• 3.6 V tolerant inputs

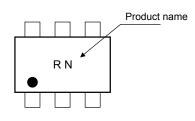


Weight: 0.003 g (typ.)

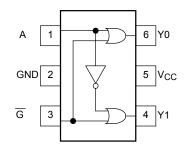
#### Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Value	Unit
Power supply voltage	V <sub>CC</sub>	-0.5~4.6	V
DC input voltage	VIN	-0.5~4.6	V
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5 (Note 1)	V
Input diode current	IIK	-50	mA
Output diode current	I <sub>OK</sub>	±50 (Note 2)	mA
DC output current	IOUT	+50	mA
Power dissipation	PD	150	mW
DC V <sub>CC</sub> /ground current	ICC	±100	mA
Storage temperature	T <sub>stg</sub>	-65~150	°C

Marking



#### Pin Assignment (top view)



Note 1: High or Low state. The  $I_{OUT}$  maximum rating must be adhere to. Note 2:  $V_{OUT} < GND$ ,  $V_{OUT} > V_{CC}$ 

# <u>TOSHIBA</u>

#### Truth Table

Inp	outs	Out	puts	
Enable	Select	VO	V/4	Selected Output
ĪG	А	Y0	Y1	
Н	Х	Н	Н	None
L	L	L	Н	Y0
L	Н	Н	L	Y1

#### **Recommended Operating Conditions**

Characteristics	Symbol	Value	Unit
Power supply voltage	Vcc	1.4~3.6	V
Tower supply voltage	vcc	1.2~3.6 (Note 3)	v
Input voltage	V <sub>IN</sub>	-0.3~3.6	V
Output voltage	Vout	0~V <sub>CC</sub> (Note 4)	V
		±24 (Note 5)	
Output Current	IOH/IOL	±18 (Note 6)	mA
		±4 (Note 7)	
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rise and fall time	d <sub>t</sub> /d <sub>v</sub>	0~10 (Note 8)	ns/V

Note 3: Data retention only

Note 4: High or Low state

Note 5:  $V_{CC} = 3.0 \sim 3.6 \text{ V}$ 

Note 6:  $V_{CC} = 2.3 \sim 2.7 \text{ V}$ 

Note 7:  $V_{CC} = 1.4 \sim 1.9 \text{ V}$ 

Note 8:  $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$ 

### DC Electrical Characteristics (Ta = –40~85°C, 2.7 V < $V_{CC} \leq$ 3.6 V)

Characteristics	Symbol	Test C		Min	Max	Unit			
Characteristics	Symbol	Test C			IVIIII	IVIAA	Offic		
High-Level Input Voltage	VIH			2.7~3.6	2.0	_	v		
Low-Level Input Voltage	VIL			2.7~3.6	_	0.8	v		
			I <sub>OH</sub> = -100 μA	2.7~3.6	V <sub>CC</sub> - 0.2	_			
High-Level Output Voltage	V <sub>OH</sub>	$V_{OH}$ $V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -12 mA	2.7	2.2	_	V		
	-		I <sub>OH</sub> = -18 mA	3.0	2.4	_			
			I <sub>OH</sub> = -24 mA	3.0	2.2	_			
		VIN = VIH or VIL			I <sub>OL</sub> = 100 μA	2.7~3.6	_	0.2	
			I <sub>OL</sub> = 12 mA	2.7	_	0.4	v		
Low-Level Output Voltage	VOL		I <sub>OL</sub> = 18 mA	3.0	_	0.4	v		
			I <sub>OL</sub> = 24 mA	3.0	_	0.55			
Input Leakage Current	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		2.7~3.6	_	±10.0	μA		
Quiescent Supply Current	1.5.5	$V_{IN} = V_{CC}$ or GNI	D	2.7~3.6	_	20.0			
Quiescent Supply Current	Icc	$V_{CC} \leq V_{IN} \leq 3.6$	6 V	2.7~3.6		±20.0	μA		
Increase in I <sub>CC</sub> per Input	Δlcc	$V_{IH} = V_{CC} - 0.6$ V	/	2.7~3.6	_	750			

#### DC Electrical Characteristics (Ta = -40~85°C, 2.3 V $\leq$ V<sub>CC</sub> $\leq$ 2.7 V)

Characteristics	Symbol	Test C	andition		Min	Мах	Unit				
Characteristics	Symbol	Test C	Test Condition		IVIIII	Wax	Offic				
High-Level Input Voltage	VIH			2.3~2.7	1.6	_	v				
Low-Level Input Voltage	V <sub>IL</sub>			2.3~2.7	_	0.7	v				
		$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OH</sub> = -100 μA	2.3~2.7	V <sub>CC</sub> - 0.2	_					
High-Level Output Voltage	V <sub>OH</sub>		$V_{IN} = V_{IH} \text{ or } V_{II}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OH</sub> = -6 mA	2.3	2.0	V	V
	-		$I_{OH} = -12 \text{ mA}$	2.3	1.8	_					
			I <sub>OH</sub> = -18 mA	2.3	1.7	_					
			$I_{OL} = 100 \ \mu A$	2.3~2.7	_	0.2	v				
Low-Level Output Voltage	Vol	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OL</sub> = 12 mA	2.3	_	0.4	v				
		-	I <sub>OL</sub> = 18 mA	2.3	_	0.6					
Input Leakage Current	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		2.3~2.7		±10.0	μA				
Quiescent Supply Current		$V_{IN} = V_{CC}$ or GND		2.3~2.7	_	20.0					
Quiescent Supply Current	Icc	$V_{CC} \leq V_{IN} \leq 3.6$	$V_{CC} \leq V_{IN} \leq 3.6 V$			±20.0	μA				

#### DC Electrical Characteristics (Ta = $-40 \sim 85^{\circ}$ C, 1.4 V $\leq V_{CC} < 2.3$ V)

Characteristics	Symbol	Test C	Test Condition		Min	Мах	Unit
Characteristics	Symbol			V <sub>CC</sub> (V)	IVIIII	Wax	Offic
High-Level Input Voltage	V <sub>IH</sub>	—		1.4~2.3	V <sub>CC</sub> × 0.7	_	V
Low-Level Input Voltage	V <sub>IL</sub>	_		1.4~2.3		V <sub>CC</sub> × 0.13	v
High-Level Output Voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -100 μA	1.4	V <sub>CC</sub> - 0.2	_	V
			I <sub>OH</sub> = -4 mA	1.4	1.0	_	
Low-Level Output Voltage	Vol	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	$I_{OL} = 100 \ \mu A$	1.4		0.2	v
Low-Level Output Voltage	VOL	VIN - VIH OL VIL	I <sub>OL</sub> = 4 mA	1.4		0.3	v
Input Leakage Current	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		1.4		±10.0	μA
Quiescent Supply Current		$V_{IN} = V_{CC}$ or GND		1.4	_	20.0	μA
	ICC	$V_{CC} \leq V_{IN} \leq 3.6$	ŝ V	1.4		±20.0	μΑ

#### AC Electrical Characteristics (Ta = $-40 \sim 85^{\circ}$ C, input t<sub>r</sub> = t<sub>f</sub> = 2.0 ns)

Characteristics	Symbol	Test Condition			Min	Max	Unit									
	- ,			V <sub>CC</sub> (V)		-										
				$1.5\pm0.1$	1.8	10.0										
		CL	C <sub>L</sub> =15pF,	$1.8\pm0.15$	1.5	8.0	ns									
		$R_L = 1M\Omega$	$2.5\pm0.2$	0.8	3.9	115										
Propagation delay time	t <sub>pLH</sub>			t <sub>pLH</sub>		$\textbf{3.3}\pm\textbf{0.3}$	0.6	3.3								
$(A \text{ or } \overline{G} - Y0 \text{ or } Y1)$	t <sub>pHL</sub>	t <sub>pHL</sub>	t <sub>pHL</sub>	t <sub>pHL</sub>	t <sub>pHL</sub>	t <sub>pHL</sub>	t <sub>pHL</sub>	(Figure 1 and 2)		(Figure Fund 2)			$1.5\pm0.1$	2.0	13.0	
			C <sub>L</sub> =30pF,	1.8 ± 0.15	1.8	9.5	20									
			R <sub>L</sub> =500Ω	$2.5\pm0.2$	1.2	5.0	ns									
			$\textbf{3.3}\pm\textbf{0.3}$	1.0	4.0											

For  $C_L$  = 50 pF, add approximately 300 ps to the AC maximum specification.

#### **Capacitive Characteristics (Ta = 25°C)**

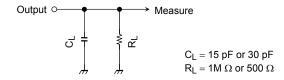
Characteristics	Symbol	Test Condition			TYP.	Unit
Characteristics	Symbol			V <sub>CC</sub> (V)	TTP.	Unit
Input Capacitance	C <sub>IN</sub>	—		1.8, 2.5, 3.3	6	pF
Power Dissipation Capacitance	C <sub>PD</sub>	$f_{IN} = 10 \text{ MHz}$	(Note 9)	1.8, 2.5, 3.3	20	pF

Note 9: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation:

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

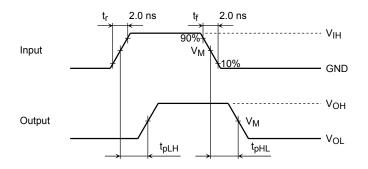
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#### Figure 1 Test Circuit



#### **AC Waveforms**

### Figure 2 t<sub>pLH</sub>, t<sub>pHL</sub>



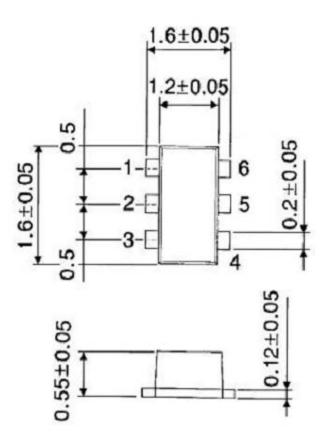
Symbol	V <sub>CC</sub>					
Symbol	$3.3\pm0.3~V$	$2.5\pm0.2\;V$	$1.8\pm0.15~V$	$1.5\pm0.1~\text{V}$		
VIH	2.7 V	V <sub>CC</sub>	V <sub>CC</sub>	V <sub>CC</sub>		
VM	1.5 V	V <sub>CC</sub> /2	V <sub>CC</sub> /2	V <sub>CC</sub> /2		

### TOSHIBA

#### Package Dimensions

SON6-P-0.50

Unit : mm



Weight: 0.003 g (typ.)

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